


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/092,109	TWOMEY ET AL.	
	Examiner	Art Unit	
	Binh Q. Nguyen	2664	

SEARCHED			
Class	Subclass	Date	Examiner
370	395.1	12/19/2005	BQN
370	395.64	12/19/2005	BQN
370	395.7	12/19/2005	BQN
370	395.6	12/19/2005	BQN
370	394	12/19/2005	BQN
370	474	12/19/2005	BQN

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST (US-GPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM-TDB), see more on search history.	12/19/2005	BQN
Consulted with Andrew Lee	12/19/2005	BQN